
 ESCC		APPLICATION FOR EXTENSION OF ESCC QUALIFICATION APPROVAL			Page 1 Appl. No. 286D
Component Title: Capacitors, Microwave, Silicon, MOS, Naked Die based on Types 101M, 201M, 400M and 401M		Executive Member: CNES			Date: 07/03/2017
Components (including series and families) submitted for Extension of Qualification Approval:					1
ESCC COMPONENT NO.	VARIANTS	RANGE OF COMPONENTS	BASED ON	TEST VEHICLE / S	COMPONENT SIMILAR
5711/002	01 to 31	40V to 200 V	400M	400M110A101M 400M107A390M	
					201M (200V) 101M (100V)
Component Manufacturer Cobham Microwave		Location of Manufacturing Plant(s) 31, avenue de la Baltique 91978 Villebon-sur-Yvette Cedex France		Date of original qualification approval: Date: 15/12/2008 Certificate Ref No. 286	
ESCC Specifications used for Maintenance of qualification testing: Generic: 5010 Issue: 2 Detail(s): 5711/002 Issue: 3		Deviations to LVT testing and Detail Specification used: No <input checked="" type="checkbox"/> Yes <input type="checkbox"/> (supply details in Box 15) Deviation from current Specifications: No <input checked="" type="checkbox"/> Yes <input type="checkbox"/> (Supply details)		Qualification Extension Report reference and date: 2017016665-223 dated 10/01/2017 2017027086-223 dated 25/02/2016	
Summary of procurement or equivalent test results during current validity period in support of this application (those to ESCC listed first)					8
Project Name	Testing Level	LAT	Date code	Quantity Delivered	
Various		LAT2/Chart F4B	2015 and 2016	>120 000	
PID changes since start of qualification None <input checked="" type="checkbox"/> Minor* <input type="checkbox"/> Major* <input type="checkbox"/> *Provide details in box: Click here to enter text.		Current PID Verified by: CNES Ref No: PID 302 Issue: H Rev Date: 01/03/2017		Name of Executive Representative Date: 01/03/2017	
Current Manufacturing facilities surveyed by: ESA and CNES on 24/09/2014 (Name of Executive Representative) (Date) Satisfactory: Yes <input checked="" type="checkbox"/> No <input type="checkbox"/> Explain Report Reference: COBH-CIRC-AUD-2014					11

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Non compliance to ESCC requirements: 15


No.:	Specification	Paragraph	Non compliance

Additional tasks required to achieve full compliance for ESCC qualification or rationale for acceptability of noncompliance: 16

Executive Manager Disposition 17

Application Approval: Yes ☒ No ☐


Action / Remarks:



Franco Ongaro
 Director of Technology, Engineering and Quality
 Head of ESA/ESTEC Establishment

Date:

 Signature, ESA Representative

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ANNEX 1: LIST OF TESTS DONE TO SUPPORT EXTENSION OF QUALIFICATION

Tests conducted in compliance with:

- ESCC 5010 generic specification; Chart V (for ESCC/QPL parts);
- Or PID-TFD (for ESCC/QML parts)

Tests vehicle identification/description:

400M110A101M	
400M107A390M	

Detail Specification reference: 5711/002

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Chart V	Test	Tick when done	Conditions	Date Code Diffusion Lot	Tested Qty	No. of Rejects	Comments if not performed. Comments on Rejection
Environmental/Mechanical Subgroups	Thermal Shock Test	<input type="checkbox"/>	ESCC 5010 Para. 9.5.2				Not required (naked die)
	Shock Test	<input type="checkbox"/>	MIL-STD-750 Test Method 2016				Not required (naked die)
	Vibration Test	<input type="checkbox"/>	MIL-STD-750 Test Method 2056				Not required (naked die)
	Constant Acceleration	<input type="checkbox"/>	MIL-STD-750 Test Method 2006				Not required (naked die)
	Seal Test	<input type="checkbox"/>	MIL-STD-750 Test Method 1071				Not required (naked die)
	Moisture Resistance	<input type="checkbox"/>	MIL-STD-750 Test Method 1021				Not required (naked die)
	Seal Test	<input type="checkbox"/>	MIL-STD-750 Test Method 1071				Not required (naked die)
	Electrical Measurements at Room Temp.	<input type="checkbox"/>	Table 2 of the Detail Specification				Not required (naked die)
	External Visual Inspection	<input type="checkbox"/>	ESCC Basic Specification No. 20500				Not required (naked die)
Endurance Subgroup	Operating Life	<input checked="" type="checkbox"/>	MIL-STD-750 Test Method 1026	1550 1622	8 + 8	0	
	Electrical Measurements during Endur. Test	<input checked="" type="checkbox"/>	Table 6 of the Detail Specification	1550 1622	8 + 8	0	
	External Visual Inspection	<input type="checkbox"/>	ESCC Basic Specification No. 20500				Not required (naked die)



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Chart V	Test	Tick when done	Conditions	Date Code Diffusion Lot	Tested Qty	No. of Rejects	Comments if not performed. Comments on Rejection
Electrical Subgroup – Electrical Measurements	Electrical Measurements at Room Temp.	<input type="checkbox"/>	Table 2 of the Detail Specification				Not required (naked die)
	Electrical Measurements at High & Low Temp's	<input type="checkbox"/>	Table 3 of the Detail Specification				Not required (naked die)
	External Visual Inspection	<input type="checkbox"/>	ESCC Basic Specification No. 20500				Not required (naked die)
	Special Testing	<input type="checkbox"/>	The Detail Specification				Not required (naked die)
Electrical Subgroup – Assembly Capability Tests	Solderability Test	<input type="checkbox"/>	MIL-STD-750 Test Method 2026				Not required (naked die)
	Permanence of Marking	<input type="checkbox"/>	ESCC Basic Specification No. 24800				Not required (naked die)
	Terminal Strength	<input type="checkbox"/>	MIL-STD-750 Test Method 2036				Not required (naked die)
De-encapsulation Sub group	Internal Visual Inspection	<input type="checkbox"/>	ESCC Basic Specification No. 20400				Not required (naked die)
	Bond Strength	<input checked="" type="checkbox"/>	MIL-STD-750 Test Method 2037	1550 1622	3 + 4	0	
	Die Shear	<input checked="" type="checkbox"/>	MIL-STD-750 Test Method 2017	1550 1622	3 + 4	0	

	<p align="center">APPLICATION FOR EXTENSION OF ESCC QUALIFICATION APPROVAL</p> <p>Component title: Capacitors, Microwave, Silicon, MOS, Naked Die based on Types 101M, 201M, 400M and 401M</p> <p>Executive Member: CNES Date: 07/03/2017</p>	<p align="center">Page 7</p> <p align="center">Appl. No. 286D</p>
<p align="center">NOTES ON THE COMPLETION OF THE APPLICATION FORM FOR ESCC QUALIFICATION EXTENSION APPROVAL</p>		
<p>ENTRIES</p>		
Form heading	<p>shall indicate: - the title of the component as given in its detail specification or the name of the series, family; - the Executive Member; - the entering date; - the certificate number and its sequential suffix.</p>	
Box 1	<p>shall provide details given in the table; in particular there shall be listed: - the variants or range of variants; - the range of components (the ESCC code is recommended to indicate the values or values range, the tolerance, the voltage, etc); the designation given in the detail specification as 'base on'; - under Test Vehicle enter either an ESCC code or the specific characteristic capable of identifying the component tested (e.g., voltage of coil for a relay); - under component similar enter a cross if relevant.</p>	
Box 2; 3 and 4	<p>As per QPL entry; otherwise, an explanation of the changes must be supplied.</p>	
Box 5	<p>Will show the ESCC Generic and Detail specifications, including issue number and revision letter, current at the time the tests reported were performed. If the specifications are different from those current on the date of the application, see Box 6.</p>	
Box 6	<p>Will show the deviations from the Generic and Detail Specifications listed in Box 5, in particular deviations from testing. In case of deviations this must be listed in Box 15. In case the referenced specification in Box 5 have currently a different issue and/or revision indicate also whether the test data deviates or not from such current documents.</p>	
Box 7	<p>Must reference the report(s) supplied in support of the application.</p>	
Box 8	<p>Should provide the details of procurement to the full ESCC System, documentation of all of which should already have been delivered to the ESCC Executive under the terms of the relevant Generic Specification. An appropriate table has been drawn in this box.</p>	
Box 9	<p>If the PID evolved after the Original Qualification or after the last Extension of Qualification, adequate details of such evolution shall be provided together with the reasons for the changes. Major changes shall be clearly marked.</p>	
Box 10	<p>Identify the current PID issue status, date and actual date of verification. The date of verification of the current PID should be arranged as close as possible to the required date of extension.</p>	
Box 11	<p>This box can be completed only after a physical visit to the plant to confirm that no unexplained changes occurred and that the practices, procedures, material, etc. used in manufacturing the components are as described in the PID. This survey shall be carried out in accordance with the requirements of ESCC Basic Specification No. 20200 and its findings shall be recorded.</p>	
Box 12	<p>Provide details of, or reference to, any Destructive Physical Analysis (DPA) and Failure Analysis reports as well as any Nonconformance(s) (NCCS) occurred during the qualification validity period, stating if established corrective action have produced satisfactory results.</p>	
Box 13	<p>Enter only the name of the Executive Member (i.e., CNES, DLR, ESTEC, etc.) and the signature of the responsible Executive Coordinator.</p>	
Box 14	<p>To be used when there is a need to expand any of the boxes from 1 through 12. Identify box affected and reference the Box 14 in the relevant Box. Box 14 can be broken into 14a, 14b, etc. if several boxes have to be expanded.</p>	
Box 15	<p>Fill in Table as requested.</p>	
Box 16	<p>Any additional action deemed necessary by the Executive Member to bring the submitted data to a standard likely to be accepted by the ESCC Executive should be listed herein or the reason(s) to accept the noncompliance.</p>	
Box 17	<p>All Executive Manager recommendations on the application itself, special conditions or restrictions, modifications of the QPL or QML entry, letters to the manufacturer, etc. shall be entered clearly in Box 19, signed by the representative for ESA, and dated.</p>	
Box 18	<p>Fill in Table as requested.</p>	
Box 19	<p>Confidential Details of PID changes including those of a confidential nature, shall be provided.</p>	
Box 20	<p>State noncompliance with reference to specification(s) and paragraph(s). To simplify reference in Box 16 each nonconformance shall be sequentially numbered. If relevant state 'None'.</p>	
Box 21	<p>Any additional action deemed necessary by the Executive Member to bring the submitted data to a standard likely to be accepted by the ESCC Executive should be listed herein or the reason(s) to accept the noncompliance.</p>	
Box 22	<p>Additional Comments.</p>	